


<b>Search Notes</b>  	<b>Application/Control No.</b>  10524587	<b>Applicant(s)/Patent Under Reexamination</b>  SERNA ET AL.
	<b>Examiner</b>  Pablo N Tran	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
370	252, 256, 310-312, 329-331, 347-349, 352, 390-392, 395.52, 428, 432	3/16/08	PT

SEARCH NOTES		
Search Notes	Date	Examiner
East/West	3/16/08	PT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner